

# **CYPRESS SEMICONDUCTOR CORPORATION**

## **PRODUCT RELIABILITY REPORT**

---

QUARTER 1, 2000



PERFORM PER THE REQUIREMENT OF 25-00008, RELIABILITY MONITOR PROGRAM SPECIFICATION

Ed Russell  
Reliability Director



## STANDARD STRESS TEST DESCRIPTIONS

<u>TEST</u>	<u>DESCRIPTION</u>
EFRA/LFRA	High Temp Op Life, 150°C, Dynamic 115% V <sub>CC</sub> Nominal
EFRA/LFRB	High Temp Op Life, 125°C, Dynamic 115% V <sub>CC</sub> Nominal
HTSSLA	High Temp Steady State Life, 150°C, Static 115% V <sub>CC</sub> Nominal
HTSSLB	High Temp Steady State Life, 125°C, Static 115% V <sub>CC</sub> Nominal
DRET	Data Retention Test, Data Bake 165°C, Plastic
DRET2	Data Retention Test, Data Bake 250°C, Hermetic
PCT	Pressure Cooker Test, 121°C, 100%RH, No Bias
HAST	Hi-Accel Saturation Test, 140°C/130°C, 85%RH, Static 100% V <sub>CC</sub> Nominal
TC1	Temp Cycle, 125°C to -40°C (Hermetic devices)
TC2	Temp Cycle, 125°C to -40°C
TC3	Temp Cycle, 150°C to -65°C
HTS	High Temp Storage, 150°C /165°C, No Bias



## WAFER FAB AREAS

<b><u>FAB #</u></b>	<b><u>LOCATION</u></b>
CA	San Jose, California
TX	Round Rock, Texas
MN	Bloomington, Minnesota
TW	TSMC, Taiwan

## ASSEMBLY LOCATION

<b><u>ID</u></b>	<b><u>COMPANY/LOCATION</u></b>
KOREA-A	Anam-Buchon/Korea
ASAT-B	Asat/Hongkong
USA-C	Cypress/USA
PHIL-D	Dynesem/Philippines
USA-E	Cypress-Minnesota/USA
INDNS-F	Astra/Indonesia
TAIWAN-G	ASE/Taiwan
KOREA-H	Hyundai/Korea
MALAY-J	ASE/Malaysia
THLAND-AK	TMS/Thailand
KOREA-L	Anam-Seoul/Korea
PHIL-M	Anam/Philippines
USA-N	Express/USA
INDNS-O	Omedata/Indonesia
USA-P	Pantronix/USA
KOREA-Q	Anam-Bupyong/Korea
CSPI-R	Cypress/Philippines
USA-S	ATM/USA
TAIWAN-T	OSE/Taiwan
MALAY-U	Unisem/Malaysia
USA-V	VLSA/USA
USA-W	Toshiba/USA
ALPHA-X	Alphatec/Thailand
THLAND-Z	Hana/Thailand
USA-AP	APLUS/USA
KOREA-GQ	Anam-Khangju/Korea
PHIL-GW	Gateway Electronics/Philippines



## DESCRIPTION OF DATA TABLE COLUMN HEADINGS

<u>COLUMN HEADING</u>	<u>DESCRIPTION OF COLUMN CONTENTS</u>
Division	Cypress Manufacturing Division
Test	Common code for the stress performed. See table on previous page for detail.
Test Condition	Tem/humidity/bias condition for the stress. See table on previous for detail
Device ID	Cypress part number
Date Code	Week in which specific lot was marked/sealed/molded.
Lot Number	Manufacturing (assembly) lot number
Function	Generic product family at Cypress
Technology	Fabrication process technology.
Pkg Type	Common code for standard package configuration (PDIP=Plastic Dual-In-Line-Package).
Pkg Location	Country Location + Initial of assembly house (see table on previous page for detail).
# Pins	Pin count of package in which device is assembled.
Duration	Data Readpoint of stress. For Temp Cycle (TC) = Cycles; all other stresses=Hours.
# Test	Quantity of devices submitted to this stress/test.
# Failed	Quantity of devices failing at this specific readpoint.
Fail Mode	Failure analysis results from this test, if any.



**RELIABILITY DATA SUMMARY**  
**(Q100)**

<b>LONG TERM FAILURE RATE SUMMARY</b>					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
E2PROM TOTAL	78,960	0	78,960	0	
CMOS-TSMC TOTAL	115,500	0	115,500	0	
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	1,379,068	0	1,379,068	5	3 UNKNOWN/2 LOST DEVICE
BICMOS TOTAL	0	0	0	0	
LFR TOTAL	1,573,528	0	1,573,528	5	3 UNKNOWN/2 LOST DEVICE
<b>EARLY FAILURE RATE SUMMARY</b>					
PROCESS	UNITS TESTED			FAILED	FAILURE MODE
	150C	125C	TOTAL		
E2PROM TOTAL	671	0	671	0	
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	46,203	0	46,203	6	2 PARTICLES/2DESTROY DURING ANALYSIS/2 POLY DEFECTS
BICMOS TOTAL	0	0	0	0	
EFR TOTAL	46,874	0	46,874	6	2 PARTICLES/2DESTROY DURING ANALYSIS/2 POLY DEFECTS
<b>HTSSL FAILURE RATE SUMMARY</b>					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	12,936	0	12,936	0	
BICMOS TOTAL	0	0	0	0	
HTSSL TOTAL	12,936	0	12,936	0	

\* Equivalent Total Device Hours/Cycles. Derating factors are used for lower stress condition.



**RELIABILITY DATA SUMMARY  
(Q100)**

TEMP CYCLE FAILURE RATE SUMMARY					
PROCESS	UNITS TESTED			FAILED	FAILURE MODE
	1000Cys Condition C	2000Cys Condition B	TOTAL		
E2PROM TOTAL	587	392	979	0	
CMOS-TSMC TOTAL	432	0	432	0	
FAMOS TOTAL	90	0	90	0	
FLASH TOTAL	975	0	975	0	
SRAM/LOGIC TOTAL	3,875	565	4,440	14	2 OPEN BOND LIFT /8 TOPSIDE CRACK/2 OPEN HEEL/1 UNKNOWN/1 DESTROY DURING ANALYSIS
BICMOS TOTAL	87	0	87	0	
TC TOTAL	6,046	957	7,003	14	2 OPEN BOND LIFT/8 TOPSIDE CRACK/2 OPEN HEEL/1 UNKNOWN/1 DESTROY DURING ANALYSIS
HAST FAILURE RATE SUMMARY					
PROCESS	UNITS TESTED			FAILED	FAILURE MODE
	140C	130C	TOTAL		
E2PROM TOTAL	48	48	96	0	
CMOS-TSMC TOTAL	0	96	96	0	
FAMOS TOTAL	0	220	220	0	
FLASH TOTAL	0	376	376	0	
SRAM/LOGIC TOTAL	48	1,606	1,605	2	1 OPEN METAL/1 UNKNOWN
BICMOS TOTAL	0	45	45	0	
HAST TOTAL	96	2,391	2,487	2	1 OPEN METAL/1 UNKNOWN



**RELIABILITY DATA SUMMARY**  
**(Q100)**

PCT FAILURE RATE SUMMARY			
PROCESS	UNITS TESTED	FAILED	FAILURE MODE
E2PROM TOTAL	326	2	2 SOLDERABILITY
FAMOS TOTAL	313	0	
FLASH TOTAL	629	0	
SRAM/LOGIC TOTAL	2,128	3	2 UNKNOWN/1 DELAMINATION IN TOPSIDE
BICMOS TOTAL	45	0	
PCT TOTAL	3,115	5	2 SOLDERABILITY/2 UNKNOWN/1 DELAMINATION IN TOPSIDE



### Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: CMOS-TSMC															
HAST	130C/5.5V	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	128	48	0	
	130C/5.5V	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	128	48	0	
HTS	150C/N/A	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	500	48	0	
	150C/N/A	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	1000	48	0	
LFRA	150C/5.75V	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	80	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	500	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	80	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	500	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	80	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	500	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	300	48	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	500	48	0	
T/C3	150C/-65C	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	500	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	1000	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	300	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	500	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	1000	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	300	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	500	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	1000	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	300	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	500	48	0	



Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: BICMOS-SM1															
HAST	130C/3.63	DCD	CHNL	CY7B991-JC	MR001130	0001	619938492	TX	PLCC	ALPHA-X	32	128	45	0	
HTS	150C/N/A	DCD	CHNL	CY7B991-JC	MR94043	9938	619926775	TX	PLCC	ALPHA-X	32	500	45	0	
PCT	121C/100%RH	DCD	CHNL	CY7B991-JC	MR001128	0001	619938492	TX	PLCC	ALPHA-X	32	168	45	0	
T/C3	150C/-65C	DCD	CHNL	CY7B991-JC	MR001129	0001	619938492	TX	PLCC	ALPHA-X	32	300	45	0	
	150C/-65C	DCD	CHNL	CY7B9910-SC	MR94035	9940	519915425	TX	SOIC	INDNS-O	24	300	42	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: E2PROM-E3															
EFRA	150C/5.75V	PLD	37K	CY37128P84-YMB	99455	9949	619936306	TW	CLCC	ALPHA-X	84	48	671	0	5 EOS
HAST	130C/3.63V	PLD	37K	CY37256VP256-BBC	99473	0001	619937560	TW	FBGA	TAIWN-G	256	128	48	0	
	140C/5.5V	PLD	37K	CY37512P208-NC	99234	9903	619817611	TW	PQFP	TAIWN-G	208	128	48	0	
HTS	165C/N/A	PLD	37K	CY37256VP256-BBC	99473	9926	619915336	TW	FBGA	TAIWN-G	256	336	48	0	
LFRA	150C/5.75C	PLD	37K	CY37064P44-YMB	99456	0002	610000497	TW	CLCC	ALPHA-X	44	80	524	0	5 EOS
	150C/5.75V	PLD	37K	CY37256P160-UMB	99457	9948	619935553	TW	CQFP	USA-GA	160	80	374	0	4 EOS
	150C/5.75V	PLD	37K	CY37512P208-UM	99461	9950	619935690	TW	CQFP	USA-GA	208	80	89	0	3 Bent Leads
PCT	121C/100%RH	PLD	37K	CY37032P44-JC	MR001147	9950	619935277	TW	PLCC	KOREA-A	44	168	45	0	
	121C/100%RH	PLD	37K	CY37032VP44-AC	MR001247	0005	610001062	TW	TQFP	TAIWN-G	44	168	45	0	
	121C/100%RH	PLD	37K	CY37064VP100-AC	MR001241	0005	610001831	TW	TQFP	TAIWN-G	100	168	45	0	
	121C/100%RH	PLD	37K	CY37128P84-JC	99455	9947	619935274	TW	PLCC	KOREA-A	84	168	48	0	
	121C/100%RH	PLD	37K	CY37128P84-JC	MR94281	9948	619932550	TW	PLCC	KOREA-A	84	168	50	0	
	121C/100%RH	PLD	37K	CY37256VP256-BBC	99473	9926	619915336	TW	FBGA	TAIWN-G	256	168	48	2	2 Solderability
	121C/100%RH	PLD	37K	CY37512P258-BGC	99461	9949	619935818	TW	BGA	TAIWN-G	292	168	45	0	
T/C1	150C/-65C	PLD	37K	CY37064P44-YMB	000606	0001	610000497	TW	CLCC	ALPHA-X	44	100	52	0	
	150C/-65C	PLD	37K	CY37064P44-YMB	000606	0001	610000497	TW	CLCC	ALPHA-X	44	1000	50	0	
T/C2	125C/-55C	PLD	37K	CY37128VP100-BBC	99473	0002	619938111	TW	FBGA	TAIWN-G	100	500	48	0	
	125C/-55C	PLD	37K	CY37128VP100-BBC	99473	0002	619938111	TW	FBGA	TAIWN-G	100	1500	48	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	0001	619937560	TW	FBGA	TAIWN-G	256	500	50	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	0001	619937560	TW	FBGA	TAIWN-G	256	1500	50	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	0001	619937561	TW	FBGA	TAIWN-G	256	500	50	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	0001	619937561	TW	FBGA	TAIWN-G	256	1500	50	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: E2PROM-E3															
T/C2	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	9949	619937559	TW	FBGA	TAIWN-G	256	500	48	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	9949	619937559	TW	FBGA	TAIWN-G	256	1500	48	0	
T/C3	150C/-65C	PLD	37K	CY37128P84-JC	99455	9947	619935274	TW	PLCC	KOREA-A	84	300	48	0	
	150C/-65C	PLD	37K	CY37128P84-JC	99455	9947	619935274	TW	PLCC	KOREA-A	84	500	48	0	
	150C/-65C	PLD	37K	CY37128P84-JC	99455	9947	619935274	TW	PLCC	KOREA-A	84	1000	48	0	
	150C/-65C	PLD	37K	CY37128P84-JC	MR94280	9948	619932550	TW	PLCC	KOREA-A	84	300	50	0	
	150C/-65C	PLD	37K	CY37256P208-NC	MR94082	9932	619921607	TW	PQFP	TAIWN-G	208	300	45	0	
	150C/-65C	PLD	37K	CY37256VP160-AC	99502	0002	619939025	TW	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	37K	CY37256VP160-AC	99502	0002	619939026	TW	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	37K	CY37256VP160-AC	99502	0002	619939027	TW	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	37K	CY37512P258-BGC	99461	9949	619935818	TW	BGA	TAIWN-G	292	300	48	0	
	150C/-65C	PLD	37K	CY37512P258-BGC	99461	9949	619935818	TW	BGA	TAIWN-G	292	500	48	0	



Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: FAMOS-P20															
HAST	130C/5.5V	PLD	PLD	PALC22V10-JC	MR001117	9950	619937875	TX	PLCC	ALPHA-X	28	128	44	0	
	130C/5.5V	PLD	PLD	PALC22V10B-15PC	MR94236	9942	519916341	TX	PDIP	INDNS-O	24	128	45	0	
PCT	121C/100%RH	PLD	MAX	CY7C344-PC	MR001002	9952	619938203	TX	PDIP	ALPHA-X	28	168	45	0	
	121C/100%RH	PLD	PLD	PALC22V10-JC	MR001115	9950	619937875	TX	PLCC	ALPHA-X	28	168	45	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: FAMOS-P26															
HAST	130C/5.5V	IPD	USB	CY7C63000A-SC	MR94114	9944	619928386	TX	SOIC	CSPI-R	20	128	45	0	
	130C/5.5V	IPD	USB	CY7C63001A-SC	MR001204	0001	610000412	TX	SOIC	CSPI-R	20	128	41	0	
	130C/5.5V	IPD	USB	CY7C634121C-OC	MR001124	9950	619938008	TX	SSOP	CSPI-R	48	128	45	0	
HTS	150C/N/A	IPD	USB	CY7C63000A-SC	MR94115	9944	619928386	TX	SOIC	CSPI-R	20	500	45	0	
	150C/N/A	IPD	USB	CY7C63001A-SC	MR001205	0001	610000412	TX	SOIC	CSPI-R	20	500	45	0	
	150C/N/A	IPD	USB	CY7C63001A-SC	MR93018	9926	619918207	TX	SOIC	CSPI-R	20	500	45	0	
	150C/N/A	IPD	USB	CY7C63001A-SC	MR93018	9926	619918207	TX	SOIC	CSPI-R	20	1000	42	0	
	150C/N/A	IPD	USB	CY7C634121C-OC	MR001125	9950	619938008	TX	SSOP	CSPI-R	48	500	45	0	
	150C/N/A	IPD	USB	CY7C63413-OC	MR94104	9941	619927219	TX	SSOP	CSPI-R	48	500	45	0	
	150C/N/A	IPD	USB	CY7C63413-SC	MR001070	9952	619937138	TX	SOIC	ALPHA-X	24	500	45	0	
	150C/N/A	IPD	USB	CY7C634131C-SC	MR001052	9952	619940066	TX	SOIC	CSPI-R	24	500	45	0	
	150C/N/A	IPD	USB	CY7C65113-SC	MR94098	9935	619924810	TX	SOIC	ALPHA-X	28	500	45	0	
	150C/N/A	IPD	USB	CY7C65113-SC	MR94098	9935	619924810	TX	SOIC	ALPHA-X	28	500	45	0	
PCT	121C/100%RH	IPD	USB	CY7C63001A-SC	MR001202	0001	610000412	TX	SOIC	CSPI-R	20	168	45	0	
	121C/100%RH	IPD	USB	CY7C634121C-OC	MR001122	9950	619938008	TX	SSOP	CSPI-R	48	168	43	0	
	121C/100%RH	IPD	USB	CY7C63413-SC	MR001067	9952	619937138	TX	SOIC	ALPHA-X	24	168	45	0	
	121C/100%RH	IPD	USB	CY7C634131C-SC	MR001049	9952	619940066	TX	SOIC	CSPI-R	24	168	45	0	
	121C/100%RH	IPD	USB	CY7C65113-SC	MR94096	9935	619924810	TX	SOIC	ALPHA-X	28	168	45	0	
T/C3	150C/-65C	IPD	USB	CY7C63000A-SC	MR94113	9944	619928386	TX	SOIC	CSPI-R	20	300	45	0	
	150C/-65C	IPD	USB	CY7C63413-OC	MR94102	9941	619927219	TX	SSOP	CSPI-R	48	300	45	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: FLASH-FL28D															
HAST	130C/5.5V	PLD	FLASH	CY7C371-JC	MR001028	9949	619937632	TX	PLCC	ALPHA-X	44	128	34	0	
	130C/5.5V	PLD	FLASH	CY7C371-JC	MR001033	9949	619937632	TX	PLCC	ALPHA-X	44	128	45	0	
	130C/5.5V	PLD	FLASH	CY7C373I-JC	000102	9936	619925111	TX	PLCC	PHIL-M	84	100	54	0	
	130C/5.5V	PLD	FLASH	CY7C373I-JC	MR001023	9936	619925111	TX	PLCC	PHIL-M	84	128	54	0	
	130C/5.5V	PLD	FLASH	CY7C373I-JC	MR94061	9927	619918706	TX	PLCC	PHIL-M	84	128	45	0	
	130C/5.5V	PLD	FLASH	CY7C374I-JC	000203	9952	619937601	TX	PLCC	ALPHA-X	84	94	50	0	
	130C/5.5V	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	128	25	0	
	130C/5.5V	PLD	PLD	PALC22V10D-JC	MR001019	9952	519919372	TX	PLCC	INDNS-O	28	128	45	0	
HTS	165C/N/A	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	336	50	0	
PCT	121C/100%RH	PLD	FLASH	CY7C371-JC	MR001026	9949	619937632	TX	PLCC	ALPHA-X	44	168	45	0	
	121C/100%RH	PLD	FLASH	CY7C371-JC	MR001031	9949	619937632	TX	PLCC	ALPHA-X	44	168	45	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	000102	9927	619918706	TX	PLCC	PHIL-M	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	000102	9935	619923963	TX	PLCC	PHIL-M	84	168	52	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	000102	9945	619931928	TX	PLCC	PHIL-M	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	000203	9952	619937599	TX	PLCC	ALPHA-X	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR001007	9949	619936176	TX	PLCC	PHIL-M	84	168	45	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR001012	9949	619936176	TX	PLCC	PHIL-M	84	168	45	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR001021	9935	619923963	TX	PLCC	PHIL-M	84	168	52	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR94278	9946	619931928	TX	PLCC	PHIL-M	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR94284	9929	619918706	TX	PLCC	PHIL-M	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C374I-JC	000203	9952	619937601	TX	PLCC	ALPHA-X	84	168	50	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: FLASH-FL28D															
PCT	121C/100%RH	PLD	PLD	PALC22V10D-JC	MR001017	9952	519919372	TX	PLCC	INDNS-O	28	168	45	0	
T/C3	150C/-65C	PLD	FLASH	CY7C371-JC	MR001027	9949	619937632	TX	PLCC	ALPHA-X	44	300	45	0	
	150C/-65C	PLD	FLASH	CY7C371-JC	MR001032	9949	619937632	TX	PLCC	ALPHA-X	44	300	45	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	000102	9927	619918706	TX	PLCC	PHIL-M	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	000102	9945	619931928	TX	PLCC	PHIL-M	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	000203	9952	619937599	TX	PLCC	ALPHA-X	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	000203	9952	619937600	TX	PLCC	ALPHA-X	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	MR001013	9949	619936176	TX	PLCC	PHIL-M	84	300	45	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	MR94277	9946	619931928	TX	PLCC	PHIL-M	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	MR94283	9929	619918706	TX	PLCC	PHIL-M	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C374I-JC	000203	9952	619937601	TX	PLCC	ALPHA-X	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	500	48	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	1000	48	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909600	TX	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909600	TX	TQFP	TAIWN-G	160	500	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909600	TX	TQFP	TAIWN-G	160	1000	49	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909601	TX	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909601	TX	TQFP	TAIWN-G	160	500	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909601	TX	TQFP	TAIWN-G	160	1000	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	MR94247	9945	619929003	TX	TQFP	KOREA-Q	160	300	45	0	



Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-L20															
T/C2	125C/-55C	DCD	VME	CY7C611A-NC	M99362	9924	619916051	TX	PQFP	ASAT-B	160	500	49	0	
	125C/-55C	DCD	VME	CY7C611A-NC	M99362	9924	619916051	TX	PQFP	ASAT-B	160	1000	46	2	2 Open- Bond Lift (Die)/1 EOS
	125C/-55C	DCD	VME	CY7C611A-NC	M99362	9924	619916051	TX	PQFP	ASAT-B	160	1500	44	8	8 Topside Crack



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-L27															
HTS	165C/N/A	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	336	48	0	
PCT	121C/100%RH/	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	168	48	1	1 Delamination in Topside
T/C3	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	300	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	1000	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	300	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	1000	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	300	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	1000	48	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-L28															
EFRA	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	48	334	0	1 EOS
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	48	234	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	48	101	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9945	619933793	TW	SSOP	CSPI-R	48	48	343	0	7 EOS
	150C/5.75V	CPD	CLK	CY22037AES	000402	0004	610003291	TX	SOIC	CSPI-R	20	48	500	0	
	150C/5.75V	CPD	CLK	CY22037AES	000402	0004	610003291	TX	SOIC	CSPI-R	20	48	500	0	
	150C/5.75V	CPD	CLK	CY22037AES	001103	0004	610003291	TW	SOIC	CSPI-R	20	48	500	0	
	150C/5.75V	CPD	CLK	CY22037AES	001103	0004	610003291	TW	SOIC	CSPI-R	20	48	500	0	
HAST	130C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	128	50	0	
	130C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	128	50	0	
	130C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	128	50	0	
HTS	150C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	80	77	0	
	150C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	168	77	0	
	150C/N/A	CPD	CLK	CY2210PVC	MR001046	9945	619933123	TX	SSOP	CSPI-R	56	500	45	0	
	150C/N/A	CPD	CLK	CY2287PVC	MR94109	9936	619925423	TX	SSOP	CSPI-R	56	500	45	0	
LFRA	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	80	120	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	500	120	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	80	120	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	500	120	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9945	619933793	TW	SSOP	CSPI-R	48	80	123	0	2 EOS
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9945	619933793	TW	SSOP	CSPI-R	48	500	123	0	
PCT	121C/100%RH	CPD	CLK	CY2210PVC	MR001043	9945	619933123	TX	SSOP	CSPI-R	56	168	44	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-L28															
PCT	121C/100%RH	CPD	CLK	CY2254ASC	MR001037	9949	619937357	TX	SOIC	CSPI-R	28	168	43	0	
	121C/100%RH	CPD	CLK	CY2277APAC	MR001061	9952	619939685	TX	TSOP	CSPI-R	48	168	44	0	
	121C/100%RH	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	168	53	0	
	121C/100%RH	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	168	53	0	
	121C/100%RH	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	168	50	0	
	121C/100%RH	IPD	FCY	CY74FCT377*TQC	MR001190	0002	610000660	TX	SSOP	CSPI-R	20	168	38	0	
T/C3	150C/-65C	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	300	50	0	
	150C/-65C	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	300	50	0	
	150C/-65C	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	300	50	0	
	150C/-65C	CPD	CLK	CY2280PVC-OC	99285	9945	619933793	TW	SSOP	CSPI-R	48	300	45	0	



*Quarterly Reliability Monitor Data - 00Q1*

<i>STRESS</i>	<i>TEST COND</i>	<i>DIV</i>	<i>FUNCTION</i>	<i>DEVICE</i>	<i>EVAL #</i>	<i>DC</i>	<i>ASSY LOT</i>	<i>FAB</i>	<i>PKG</i>	<i>PKG</i>	<i># PINs</i>	<i>DURATION</i>	<i>SAMP</i>	<i>REJ</i>	<i>FAILURE MODE</i>
<i>***Wfr Process ID***: SRAM/LOGIC-L31</i>															
PCT	121C/100%RH	IPD	FCT	CY74FCT163543*PA	MR001196	9952	619939264	MN	TSOP	CSPI-R	56	168	44	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R28															
HAST	130C/5.5V	DCD	DPORT	CY7C024-AC	MR001162	0002	619938224	TX	TQFP	TAIWN-G	100	128	45	0	
	130C/5.5V	DCD	FIFO	CY7C4245-JC	MR001136	0002	619938073	TX	PLCC	PHIL-M	68	128	45	0	
	130C/5.5V	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	128	50	0	
	130C/5.5V	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	256	50	0	
	130C/5.5V	MPD	SRAM	CY7C188-VC	MR94005	9932	619922430	TX	SOJ	CSPI-R	32	128	44	1	1 EOS /1 Open Metal (Due to Void)
HTS	130C/5.5V	MPD	SRAM	CY7C192-VC	MR001210	0002	619938503	TX	SOJ	ALPHA-X	28	128	45	0	
	150C/N/A	DCD	FIFO	CY7C420-PC	MR94259	9946	519915899	TX	PDIP	INDNS-O	28	500	45	0	
	150C/N/A	DCD	FIFO	CY7C421-VC	MR94264	9944	619930419	TX	SOJ	CSPI-R	28	500	45	0	
	150C/N/A	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	500	50	0	
	150C/N/A	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	1000	50	0	
PCT	150C/N/A	MPD	SRAM	CY7C192-VC	MR001211	0002	619938503	TX	SOJ	ALPHA-X	28	500	45	0	
	121C/100%RH	DCD	DPORT	CY7C024-AC	MR001160	0002	619938224	TX	TQFP	TAIWN-G	100	168	45	0	
	121C/100%RH	DCD	DPORT	CY7C136-NC	MR001140	9950	619937010	TX	PQFP	ASAT-B	52	168	45	0	
	121C/100%RH	DCD	FIFO	CY7C421-VC	MR94262	9944	619930419	TX	SOJ	CSPI-R	28	168	45	0	
	121C/100%RH	DCD	FIFO	CY7C4245-JC	MR001134	0002	619938073	TX	PLCC	PHIL-M	68	168	45	1	1 Unknown
T/C3	121C/100%RH	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C192-VC	MR001208	0002	619938503	TX	SOJ	ALPHA-X	28	168	45	0	
	150C/-65C	DCD	DPORT	CY7C024-AC	MR001161	0002	619938224	TX	TQFP	TAIWN-G	100	300	45	0	
	150C/-65C	DCD	DPORT	CY7C136-NC	99234	9946	619933453	CA	PQFP	ASAT-B	52	300	50	0	
	150C/-65C	DCD	DPORT	CY7C136-NC	99234	9947	619935705	CA	PQFP	TAIWN-G	52	300	50	0	
	150C/-65C	DCD	DPORT	CY7C136-NC	99234	9947	619935705	CA	PQFP	TAIWN-G	52	300	50	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R28															
T/C3	150C/-65C	DCD	DPORT	CY7C136-NC	99234	9947	619935705	CA	PQFP	TAIWN-G	52	300	50	0	
	150C/-65C	DCD	DPORT	CY7C136-NC	MR001141	9950	619937010	TX	PQFP	ASAT-B	52	300	45	0	
	150C/-65C	DCD	FIFO	CY7C420-PC	MR94258	9946	519915899	TX	PDIP	INDNS-O	28	300	45	0	
	150C/-65C	DCD	FIFO	CY7C421-VC	MR94263	9944	619930419	TX	SOJ	CSPI-R	28	300	45	0	
	150C/-65C	DCD	FIFO	CY7C4801-AC	99423	9948	619932226	TX	TQFP	TAIWN-G	64	300	49	0	
	150C/-65C	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	300	50	0	
	150C/-65C	DCD	FIFO	CY7C4801-AC	99423	9948	619932228	TX	TQFP	TAIWN-G	64	300	50	0	
	150C/-65C	MPD	SRAM	CY7C188-VC	MR94004	9932	619922430	TX	SOJ	CSPI-R	32	300	45	0	
	150C/-65C	MPD	SRAM	CY7C192-VC	MR001209	0002	619938503	TX	SOJ	ALPHA-X	28	300	45	0	



Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R32															
EFRA	150C/5.75V	MPD	SRAM	CY62256-SNC	MR92106	9915	519906723	CA	SOIC	INDNS-O	28	48	149	0	
HAST	130C/5.5V	MPD	SRAM	CY62128-ZI	MR94195	9940	619904071	MN	TSOP	TAIWN-G	32	128	39	0	
LFRA	150C/5.75V	MPD	SRAM	CY62256-SNC	MR92106	9915	519906723	CA	SOIC	INDNS-O	28	96	148	1	1 Unknown Cause
	150C/5.75V	MPD	SRAM	CY62256-SNC	MR92106	9915	519906723	CA	SOIC	INDNS-O	28	500	147	1	1 Unknown Cause
T/C3	150C/-65C	MPD	SRAM	CY62256-SNC	MR94230	9942	619930304	CA	NSOIC	CSPI-R	28	300	45	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R42															
HTS	150C/N/A	MPD	SRAM	CY62127V-BAI	000204		619938873	MN	FPBGA	CSPI-R	48	500	50	0	
	150C/N/A	MPD	SRAM	CY62127V-BAI	000204		619938873	MN	FPBGA	CSPI-R	48	1000	50	0	
PCT	121C/100%RH	MPD	SRAM	CY62127V-BAI	000204		619938675	MN	FPBGA	CSPI-R	48	168	43	0	
	121C/100%RH	MPD	SRAM	CY62127V-BAI	000204		619938873	MN	FPBGA	CSPI-R	48	168	46	0	
T/C3	150C/-65C	MPD	SRAM	CY62126V-ZSI	MR94140	9935	619922725	MN	TSOP II	CSPI-R	44	300	50	0	
	150C/-65C	MPD	SRAM	CY62127V-BAI	000204		619938675	MN	FPBGA	CSPI-R	48	300	45	0	
	150C/-65C	MPD	SRAM	CY62127V-BAI	000204		619938873	MN	FPBGA	CSPI-R	48	300	47	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R42D															
EFRA	150C/3.80	DCD	FIFO	CY7C4385-SI	MR93227	9933	619922486	MN	TQFP	KOREA-Q	64	48	143	0	
	150C/3.8V	MPD	SRAM	CY7C1020V33-ZSC	000501	0002	610001575	MN	TSOP II	CSPI-R	44	48	6952	0	
	150C/3.8V	MPD	SRAM	CY7C1049V33-VC	99358	9948	619934908	MN	SOJ	KOREA-L	36	48	3980	0	
	150C/3.8V	MPD	SRAM	CY7C1049V33-VC	99358	9948	619934909	MN	SOJ	KOREA-L	36	48	3387	0	
	150C/3.8V	MPD	SRAM	CY7C1333-AC	MR92099	9901	619817590	MN	TQFP	CSPI-R	100	48	146	0	2 EOS
HAST	130C/3.63	MPD	SRAM	CY7C1021V33-VC	MR001185	0001	619938884	MN	SOJ	TAIWN-G	44	128	45	0	
	130C/3.63V	MPD	SRAM	CY7C1021V33-ZSC	MR001173	9950	619935798	MN	TSOP II	KOREA-H	44	128	45	0	
	130C/3.63V	MPD	SRAM	CY7C1049V33-VC	MR001231	0003	619939542	MN	SOJ	CSPI-R	36	128	45	0	
HTS	150C/N/A	MPD	SRAM	CY7C1021V33-VC	MR001186	0001	619938884	MN	SOJ	TAIWN-G	44	500	45	0	
	150C/N/A	MPD	SRAM	CY7C1021V33-ZSC	MR001174	9950	619935798	MN	TSOP II	KOREA-H	44	500	45	0	
	150C/N/A	MPD	SRAM	CY7C1049V33-VC	MR001232	0003	619939542	MN	SOJ	CSPI-R	36	500	45	0	
	150C/N/A	MPD	SRAM	CY7C1049V33-VC	MR94243	9945	619929938	MN	SOJ	CSPI-R	36	500	45	0	
	150C/N/A	MPD	SRAM	CY7C1334-AC	MR94202	9941	619927329	MN	TQFP	CSPI-R	100	500	45	0	
LFRA	150C/3.80V	DCD	FIFO	CY7C4385-SI	MR93227	9933	619922486	MN	TQFP	KOREA-Q	64	500	143	0	
	150C/3.8V	MPD	SRAM	CY7C1333-AC	MR92099	9901	619817590	MN	TQFP	CSPI-R	100	96	143	0	3 EOS
	150C/3.8V	MPD	SRAM	CY7C1333-AC	MR92099	9901	619817590	MN	TQFP	CSPI-R	100	500	142	0	
PCT	121C/100%RH	MPD	SRAM	CY7C1021V33-VC	MR001183	0001	619938884	MN	SOJ	TAIWN-G	44	168	45	0	
	121C/100%RH	MPD	SRAM	CY7C1021V33-ZSC	MR001171	9950	619935798	MN	TSOP II	KOREA-H	44	168	45	0	
	121C/100%RH	MPD	SRAM	CY7C1049V33-VC	MR001229	0003	619939542	MN	SOJ	CSPI-R	36	168	45	0	
	121C/100%RH	MPD	SRAM	CY7C1345-AC	MR001235	9952	619937704	MN	TQFP	CSPI-R	100	168	45	0	
T/C3	150C/-65C	MPD	SRAM	CY7C1021V33-VC	MR001184	0001	619938884	MN	SOJ	TAIWN-G	44	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1021V33-ZSC	MR001172	9950	619935798	MN	TSOP II	KOREA-H	44	300	45	0	



## Quarterly Reliability Monitor Data - 00Q1

<i>STRESS</i>	<i>TEST COND</i>	<i>DIV</i>	<i>FUNCTION</i>	<i>DEVICE</i>	<i>EVAL #</i>	<i>DC</i>	<i>ASSY LOT</i>	<i>FAB</i>	<i>PKG</i>	<i>PKG</i>	<i># PINs</i>	<i>DURATION</i>	<i>SAMP</i>	<i>REJ</i>	<i>FAILURE MODE</i>
<b>***Wfr Process ID***: SRAM/LOGIC-R42D</b>															
T/C3	150C/-65C	MPD	SRAM	CY7C1049V33-VC	MR001230	0003	619939542	MN	SOJ	CSPI-R	36	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1049V33-VC	MR94241	9945	619929938	MN	SOJ	CSPI-R	36	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1334-AC	MR94200	9941	619927329	MN	TQFP	CSPI-R	100	300	44	0	
	150C/-65C	MPD	SRAM	CY7C1345-AC	MR94136	9941	619924444	MN	TQFP	CSPI-R	100	300	50	0	
	150C/-65C	MPD	SRAM	CY7C1345-AC	MR94137	9941	619924444	MN	TQFP	CSPI-R	100	300	47	0	
	150C/-65C	MPD	SRAM	CY7C1352-AC	MR94134	9939	619913649	MN	TQFP	CSPI-R	100	300	46	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R42H															
EFRA	150C/5.75	MPD	SRAM	CY62128-ZAC	MR91134	9829	619807930	MN	STSOP	CSPI-R	32	48	148	0	1 EOS
HAST	130C/5.5V	MPD	SRAM	C62128A-ZAI	MR94273	9938	619926232	MN	STSOP	CSPI-R	32	128	45	0	
	130C/5.5V	MPD	SRAM	CY62128-SC	MR001098	9952	619937646	MN	SOIC	CSPI-R	32	128	45	0	
	130C/5.5V	MPD	SRAM	CY62256-SNC	MR001167	9949	619935207	MN	NSOIC	CSPI-R	28	128	38	0	
	130C/5.5V	MPD	SRAM	CY62256-SNI	MR94182	9942	519915797	MN	SOIC	INDNS-O	28	128	30	0	
	130C/5.5V	MPD	SRAM	CY62256-SNI	MR94182	9942	519915797	MN	SOIC	INDNS-O	28	128	30	0	
HTS	150C/N/A	MPD	SRAM	C62128A-ZAI	MR94274	9938	619926232	MN	STSOP	CSPI-R	32	500	45	0	
	150C/N/A	MPD	SRAM	CY62128-SC	MR001099	9952	619937646	MN	SOIC	CSPI-R	32	500	44	0	
	150C/N/A	MPD	SRAM	CY62128-ZAC	MR001076	0001	619938583	MN	STSOP	CSPI-R	32	500	45	0	
	150C/N/A	MPD	SRAM	CY62256-SNC	MR001168	9949	619935207	MN	NSOIC	CSPI-R	28	500	45	0	
	150C/N/A	MPD	SRAM	CY62256-SNC	MR001219	0005	510000798	MN	NSOIC	INDNS-O	28	500	45	0	
	150C/N/A	MPD	SRAM	CY62256-ZC	MR001111	9952	619938545	MN	TSOP	CSPI-R	28	500	45	0	
LFRA	150C/5.75	MPD	SRAM	CY62128-ZAC	MR91134	9829	619807930	MN	STSOP	CSPI-R	32	96	146	0	
	150C/5.75	MPD	SRAM	CY62128-ZAC	MR91134	9829	619807930	MN	STSOP	CSPI-R	32	500	142	0	
PCT	121C/100%RH	MPD	SRAM	C62128A-ZAI	MR94271	9938	619926232	MN	STSOP	CSPI-R	32	168	45	0	
	121C/100%RH	MPD	SRAM	CY62128-SC	MR001096	9952	619937646	MN	SOIC	CSPI-R	32	168	44	0	
	121C/100%RH	MPD	SRAM	CY62128-ZAC	MR001073	0001	619938583	MN	STSOP	CSPI-R	32	168	45	0	
	121C/100%RH	MPD	SRAM	CY62256-SNC	MR001165	9949	619935207	MN	NSOIC	CSPI-R	28	168	38	0	
	121C/100%RH	MPD	SRAM	CY62256-SNC	MR001216	0005	510000798	MN	NSOIC	INDNS-O	28	168	45	0	
	121C/100%RH	MPD	SRAM	CY62256-ZC	MR001108	9952	619938545	MN	TSOP	CSPI-R	28	168	45	0	
T/C3	150C/-65C	MPD	SRAM	C62128A-ZAI	MR94272	9938	619926232	MN	STSOP	CSPI-R	32	300	45	0	
	150C/-65C	MPD	SRAM	CY62128-SC	MR001097	9952	619937646	MN	SOIC	CSPI-R	32	300	45	1	1 Unknown
	150C/-65C	MPD	SRAM	CY62128-ZAC	MR001074	0001	619938583	MN	STSOP	CSPI-R	32	300	45	0	



Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R42H															
T/C3	150C/-65C	MPD	SRAM	CY62256-SNC	MR001166	9949	619935207	MN	NSOIC	CSPI-R	28	300	45	0	
	150C/-65C	MPD	SRAM	CY62256-SNC	MR001217	0005	510000798	MN	NSOIC	INDNS-O	28	300	45	0	
	150C/-65C	MPD	SRAM	CY62256-SNI	MR94181	9942	519915797	MN	SOIC	INDNS-O	28	300	45	0	
	150C/-65C	MPD	SRAM	CY62256-ZC	MR001109	9952	619938545	MN	TSOP	CSPI-R	28	300	45	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R42HD															
EFRA	150C/5.75	MPD	SRAM	CY7C199-VC	MR93075	9929	619920539	MN	SOJ	CSPI-R	28	48	150	0	
	150C/5.75V	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	48	1099	0	
	150C/5.75V	MPD	SRAM	CY7C109-VC	99452	9947	519918323	MN	SOJ	INDNS-O	32	48	3073	0	
	150C/5.75V	MPD	SRAM	CY7C109-VC	99452	9947	519918324	MN	SOJ	INDNS-O	32	48	2945	1	1 Particle Defect
	150C/5.75V	MPD	SRAM	CY7C109-VC	99452	9947	519918326	MN	SOJ	INDNS-O	32	48	1952	2	2 Destroyed During Analysis
HAST	130C/5.5V	MPD	SRAM	CY7C1009-VC	MR001082	9951	619936395	MN	SOJ	CSPI-R	32	128	45	0	
	130C/5.5V	MPD	SRAM	CY7C1020-VC	MR94091	9933	619922192	MN	SOJ	TAIWN-G	44	128	41	0	
	130C/5.5V	MPD	SRAM	CY7C1020-ZSC	MR001155	0002	610000702	MN	TSOP II	CSPI-R	44	128	45	1	1 UNKNOWN
	130C/5.5V	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	128	47	0	
	130C/5.5V	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	128	50	0	
	130C/5.5V	MPD	SRAM	CY7C109-ZC	99511	9952	619939442	MN	TSOP	TAIWN-T	32	128	50	0	
	130C/5.5V	MPD	SRAM	CY7C199-VC	000405	9949	619936486	MN	SOJ	CSPI-R	28	128	45	0	
	130C/5.5V	MPD	SRAM	CY7C199-VC	000405	9949	619936849	MN	SOJ	CSPI-R	28	128	46	0	
	130C/5.5V	MPD	SRAM	CY7C199-VC	000405	9949	619936855	MN	SOJ	CSPI-R	28	128	45	0	
	130C/5.5V	MPD	SRAM	CY7C199-VC	MR94189	9942	619929685	MN	TSOP	CSPI-R	28	128	41	0	2-EOS
	130C/5.5V	MPD	SRAM	CY7C199-VI	MR001255	0006	610004663	MN	SOJ	CSPI-R	28	128	45	0	
	140C/5.5V	MPD	SRAM	CY7C109-VC	99112	9915	619906538	MN	SOJ	INDNS-O	32	128	48	0	
HTS	150C/N/A	DCD	DPORT	CY7C09379V-AC	MR94029	9932	619921143	MN	TQFP	TAIWN-G	100	500	43	0	
	150C/N/A	MPD	SRAM	CY7C1009-VC	MR001083	9951	619936395	MN	SOJ	CSPI-R	32	500	45	0	
	150C/N/A	MPD	SRAM	CY7C1020-ZSC	MR001156	0002	610000702	MN	TSOP II	CSPI-R	44	500	45	0	
	150C/N/A	MPD	SRAM	CY7C109-VC	MR001105	9950	519919324	MN	SOJ	INDNS-O	32	500	45	0	
	150C/N/A	MPD	SRAM	CY7C109-VC	MR94176	9942	519916020	MN	SOJ	INDNS-O	32	500	45	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R42HD															
HTS	150C/N/A	MPD	SRAM	CY7C109-ZC	99511		619939442	MN	TSOP	TAIWN-T	32	500	52	0	
	150C/N/A	MPD	SRAM	CY7C109-ZC	99511		619939442	MN	TSOP	TAIWN-T	32	1000	52	0	
	165C/N/A	MPD	SRAM	CY7C109-VC	99112	9915	619906538	MN	SOJ	INDNS-O	32	336	48	0	
	165C/N/A	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	336	50	0	
	165C/N/A	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	1000	50	0	
LFRA	150C/5.75	MPD	SRAM	CY7C199-VC	MR93075	9929	619920539	MN	SOJ	CSPI-R	28	500	150	1	1 Unknown Cause
PCT	121C/100%RH	MPD	SRAM	CY7C1009-VC	MR001080	9951	619936395	MN	SOJ	CSPI-R	32	168	45	0	
	121C/100%RH	MPD	SRAM	CY7C1020-ZSC	MR001153	0002	610000702	MN	TSOP II	CSPI-R	44	168	45	1	1 Unknown Cause
	121C/100%RH	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	168	47	0	
	121C/100%RH	MPD	SRAM	CY7C109-VC	MR001102	9950	519919324	MN	SOJ	INDNS-O	32	168	45	0	
	121C/100%RH	MPD	SRAM	CY7C109-ZC	99511	0002	619939441	MN	TSOP	TAIWN-T	32	168	48	0	
	121C/100%RH	MPD	SRAM	CY7C109-ZC	99511	0002	619939442	MN	TSOP	TAIWN-T	32	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C109-ZC	99511	0002	619939443	MN	TSOP	TAIWN-T	32	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C199-VC	000405	9949	619936955	MN	SOJ	CSPI-R	28	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C199-VC	000405	9949	619936957	MN	SOJ	CSPI-R	28	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C199-VC	000405	9952	619939305	MN	SOJ	CSPI-R	28	168	50	0	
T/C3	150C/-65C	DCD	DPORT	CY7C09379V-AC	MR94028	9932	619921143	MN	TQFP	TAIWN-G	100	300	43	0	
	150C/-65C	MPD	SRAM	CY7C1009-VC	MR001081	9951	619936395	MN	SOJ	CSPI-R	32	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1020-VC	MR94090	9933	619922192	MN	SOJ	TAIWN-G	44	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1021-VI	MR93124	9930	619919776	MN	SOJ	CSPI-R	44	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1041-VC	MR94146	9939	619927406	MN	SOJ	CSPI-R	44	300	47	0	
	150C/-65C	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	300	48	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R42HD															
T/C3	150C/-65C	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	500	48	0	
	150C/-65C	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	1000	47	0	
	150C/-65C	MPD	SRAM	CY7C109-VC	99112	9915	619906538	MN	SOJ	INDNS-O	32	300	46	0	
	150C/-65C	MPD	SRAM	CY7C109-VC	99112	9915	619906538	MN	SOJ	INDNS-O	32	1000	46	0	
	150C/-65C	MPD	SRAM	CY7C109-VC	MR001103	9950	519919324	MN	SOJ	INDNS-O	32	300	45	0	
	150C/-65C	MPD	SRAM	CY7C109-VC	MR94174	9942	519916020	MN	SOJ	INDNS-O	32	300	45	0	
	150C/-65C	MPD	SRAM	CY7C109-VIB	99112	9916	619906498	MN	SOJ	INDNS-O	32	300	46	0	
	150C/-65C	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	300	50	0	
	150C/-65C	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	500	50	0	
	150C/-65C	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	1000	50	0	
	150C/-65C	MPD	SRAM	CY7C109-ZC	99511	0002	619939441	MN	TSOP	TAIWN-T	32	300	48	0	
	150C/-65C	MPD	SRAM	CY7C109-ZC	99511	0002	619939442	MN	TSOP	TAIWN-T	32	300	50	0	
	150C/-65C	MPD	SRAM	CY7C109-ZC	99511	0002	619939443	MN	TSOP	TAIWN-T	32	300	50	0	
	150C/-65C	MPD	SRAM	CY7C1351-AC	MR94131	9932	619919041	MN	TQFP	CSPI-R	100	300	47	2	2 Open- Heel or Neck Break
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936486	MN	SOJ	CSPI-R	28	300	48	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936849	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936855	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936859	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936895	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936955	MN	SOJ	CSPI-R	28	300	47	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936956	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936957	MN	SOJ	CSPI-R	28	300	50	0	



Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R42HD															
T/C3	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936966	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619937048	MN	SOJ	CSPI-R	28	300	49	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R52D-3															
EFRA	150C/3.8V	DCD	DPORT	CY7C056V-ACB	99491	9946	619932870	MN	TQFP	TAIWN-G	100	48	80	0	
	150C/3.8V	MPD	SRAM	CY7C1325B-ACB	99503		619927801	MN	TQFP	CSPI-R	100	48	1799	0	
	150C/3.8V	MPD	SRAM	CY7C1338B-AC	99503	9946	619934137	MN	TQFP	CSPI-R	100	48	1500	0	
HAST	130C/3.63V	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	128	50	0	
	130C/3.63V	MPD	SRAM	CY7C1325B-ACB	99503	9918	619910139	MN	TQFP	CSPI-R	100	128	47	0	
LFRA	150C/3.8V	MPD	SRAM	CY7C1049BV33-VC	000305	9949	619937741	MN	SOJ	CSPI-R	36	80	530	0	
	150C/3.8V	MPD	SRAM	CY7C1049BV33-VC	000305	9949	619937741	MN	SOJ	CSPI-R	36	500	530	0	
	150C/3.8V	MPD	SRAM	CY7C1325B-ACB	99503		619927801	MN	TQFP	CSPI-R	100	80	400	0	
	150C/3.8V	MPD	SRAM	CY7C1325B-ACB	99503		619927801	MN	TQFP	CSPI-R	100	500	400	2	2 Lost Device
	150C/3.8V	MPD	SRAM	CY7C1338B-AC	99503	9946	619934137	MN	TQFP	CSPI-R	100	80	400	0	
	150C/3.8V	MPD	SRAM	CY7C1338B-AC	99503	9946	619934137	MN	TQFP	CSPI-R	100	500	400	0	
	150C/3.8V	MPD	SRAM	CY7C1338B-AC	99503	9946	619934137	MN	TQFP	CSPI-R	100	500	400	0	
PCT	121C/100%RH	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	168	48	0	
	121C/100%RH	MPD	SRAM	CY7C1325B-ACB	99503	9914	619907775	MN	TQFP	CSPI-R	100	168	47	0	
	121C/100%RH	MPD	SRAM	CY7C1329-AC	MR001222	0004	610000079	MN	TQFP	TAIWN-G	100	168	45	0	
T/C3	150C/-65C	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	300	48	0	
	150C/-65C	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	500	48	0	
	150C/-65C	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	1000	48	0	
	150C/-65C	MPD	SRAM	CY7C1325B-ACB	99503	9914	619907775	MN	TQFP	CSPI-R	100	300	40	0	7 EOS
	150C/-65C	MPD	SRAM	CY7C1325B-ACB	99503	9918	619910139	MN	TQFP	CSPI-R	100	300	47	0	
	150C/-65C	MPD	SRAM	CY7C1325B-ACB	99503	9918	619910139	MN	TQFP	CSPI-R	100	500	47	0	
	150C/-65C	MPD	SRAM	CY7C1325B-ACB	99503	9918	619910139	MN	TQFP	CSPI-R	100	1000	47	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R52H															
EFRA	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	0009	610006394	MN	SOIC	TAIWN-G	32	48	1090	0	1 Good Device
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	0009	610006395	MN	SOIC	TAIWN-G	32	48	1074	0	
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	0009	610007711	MN	SOIC	TAIWN-G	32	48	1088	0	
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	9947	619933589	MN	SOIC	TAIWN-G	32	48	1098	0	
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	9947	619933593	MN	SOIC	TAIWN-G	32	48	2186	2	2 Poly Defect
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	9947	619933598	MN	SOIC	TAIWN-G	32	48	1097	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R52LD-3															
EFRA	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		610002413	MN	FPBGA	CSPI-R	48	48	544	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	48	339	1	1 Particle Defect
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938874	MN	FPBGA	CSPI-R	48	48	402	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	48	281	0	
	150C/3.8V	MPD	SRAM	CY62137VL-ZSIB	99357	9949	619935917	MN	TSOP II	CSPI-R	44	48	3176	0	
	150C/3.8V	MPD	SRAM	CY62137VL-ZSIB	99357	9949	619935918	MN	TSOP II	CSPI-R	44	48	3313	0	
HAST	130C/3.63V	MPD	SRAM	CY62137VL-BAI	000204	0001	619938755	MN	FPBGA	CSPI-R	48	128	50	0	
	130C/3.63V	MPD	SRAM	CY62137VL-BAI	000204	0001	619938755	MN	FPBGA	CSPI-R	48	128	48	0	
	130C/3.63V	MPD	SRAM	CY62137VL-BAI	000204	0001	619938875	MN	FPBGA	CSPI-R	48	128	47	0	
	130C/3.63V	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	128	54	0	
HTS	150C/N/A	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	500	50	0	
	150C/N/A	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	1000	50	0	
	150C/N/A	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	336	48	0	
	150C/N/A	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	500	48	0	
	150C/N/A	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	1000	48	0	
LFRA	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	80	120	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	500	120	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938874	MN	FPBGA	CSPI-R	48	80	120	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938874	MN	FPBGA	CSPI-R	48	500	118	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	80	120	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	500	120	0	



## Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
***Wfr Process ID***: SRAM/LOGIC-R52LD-3															
PCT	121C/100%RH	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	168	50	0	
	121C/100%RH	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	168	50	0	
	121C/100%RH	MPD	SRAM	CY62137VL-BAI	MR001087	9949	619937534	MN	FPBGA	TAIWN-G	48	168	45	0	
	121C/100%RH	MPD	SRAM	CY62137VL-BAI	MR001091	9949	619937436	MN	FPBGA	TAIWN-T	48	168	45	0	
	121C/100%RH	MPD	SRAM	CY62137VL-BAI	MR94267	9941	619929591	MN	FPBGA	TAIWN-T	48	168	45	0	
	121C/100%RH	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925642	MN	FPBGA	TAIWN-G	48	168	50	0	
T/C2	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925642	MN	FPBGA	TAIWN-G	48	500	48	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925642	MN	FPBGA	TAIWN-G	48	1000	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925642	MN	FPBGA	TAIWN-G	48	1500	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925643	MN	FPBGA	TAIWN-G	48	500	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925643	MN	FPBGA	TAIWN-G	48	1000	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925643	MN	FPBGA	TAIWN-G	48	1500	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	500	48	1	1 Destroyed During Analysis
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	1000	48	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	1500	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	1500	47	0	
T/C3	150C/-65C	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	300	47	0	
	150C/-65C	MPD	SRAM	CY62137VL-BAI	000204		619938874	MN	FPBGA	CSPI-R	48	300	50	0	
	150C/-65C	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	300	47	0	